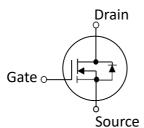


SPQR8N40WP

SYMBOL

40V N-Channel MOSFET

- Advanced Split Gate Device Design and Processes
- High Reliability Capability
- 100% CP Probing



Electrica	al Characteristics in C/P Test	t (T」a	ıt 25 °	C)		
Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Condition
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	40		_	٧	$V_{GS} = 0V$, $I_D = 250\mu A$
R _{DS(ON)}	Static Drain-Source On-Resistance	_	0.5	0.8	mΩ	$V_{GS} = 10V, I_D = 1A^{(1)}$
V _{GS (th)}	Gate Threshold Voltage	2	l	4	٧	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$
I _{DSS}	Drain-to-Source Leakage Current	_	_	1	μΑ	V _{DS} =40V, V _{GS} =0V
I _{GSS}	Gate-to-Source Leakage Current	-100		100	nA	$V_{DS} = 0V$, $V_{GS} = \pm 20V$
T _J , T _{STG}	Operating and Storage Temperature	-55°C to 150°C Max.				

Mechanical Data		Die Drawing
Chip Size ⁽²⁾	3901 μm X 3149 μm	
Gate Pad Size	170 μm X 170 μm	
Source Pad Size	3621 X 1348 μm	3901.18um
Scribe Line Width	60 µm	
Wafer Thickness	100 µm	1348.3u
Wafer Diameter	200 mm	3621.18um
Gross Die	2212 EA	Bull and
Source Metallization	Al-Cu (4µm typical)	3621.18um
Drain Metallization	Ti-Ni-Ag	3154.63um 170um
Passivation	SiN	
Recommended Storage Environment	Store in original container, in dry nitrogen, 6 months at ambient temperature of 23°C ± 3°C	

⁽¹⁾ Pulse Width tp = < 1 mS, Duty Cycle < 2%.

⁽²⁾ Chip size not include scribe line.



SPQR8N40WP

Version: 1.0

Specific Assembly Info	rmation Bill of Material (BOM)	Die Drawing
Package Type	DFN5*6	
Die Attach Method Soft solder		3901.18um
Soft Solder Composition	Pb,Sn,Ag	1348.3um
Gate Wire Bonding	Cu, 2 mil x1	3621.18um
Source Wire Bonding	Al Ribbon 40mil*4mil*2	3621.18um 4
Molding Compound Manufacturer	G700HF	170um
Solder Plating Composition	Pure Tin	

	Pos	ition	Bonding Diagram Top View
	X (μm)	Υ (μm)	
ZERO	0	0	TOP S5
ТОР	3901.2	3148.5	55
S1	140	140	54
S2	3761.2	1488.3	\$2
S3	3294.6	586.7	S3 S1
S4	140	1660.2	ZERO G1
S5	3761.2	3008.5	
G1	3694.6	36.7	
G2	3864.6	206.7	



SPQR8N40WP

Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Condition
I _{DSS}	Drain-to-Source Leakage Current	_	_	1	μΑ	V _{DS} =40V, V _{GS} =0V
I _{GSSF}	Gate-to-Source Leakage Current	_	_	100	nA	V _{DS} =0V, V _{GS} =+20V
I _{GSSR}	Gate-to-Source Leakage Current	-100	_		nA	V _{DS} =0V, V _{GS} =-20V
BV _{DSS}	Drain-Source Breakdown Voltage	40	_		V	V _{GS} =0V, I _D =250μA
BV _{DSS}	Drain-Source Breakdown Voltage	40	_		V	$V_{GS} = 0V, I_D = 1mA$
R _{DS(ON)}	Static Drain-Source On-Resistance	_	_	1.5	mΩ	V _{GS} =10V, I _D =20A
V _{GS (th)}	Gate Threshold Voltage	2	_	4	V	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$
V_{SD}	Body Diode Forward Voltage	_	_	1.2	V	V _{GS} =0V, I _{SD} =20A
I _{AS}	Avalanche Current				Α	V_{DD} =40V, V_{GS} =10V, R_{G} =25 Ω , L=0.5mH
T _J , T _{STG}	Operating and Storage Temperature	-55	_	150	°C	

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